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DCR1610F28

Phase Control Thyristor

Preliminary Information

DS5928-1.1 July 2009 (LN26822)

FEATURES

- Double Side Cooling
- High Surge Capability

APPLICATIONS

- High Power Drives
- High Voltage Power Supplies
- Static Switches

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V _{DRM} and V _{RRM} V	Conditions
DCR1610F28 DCR1610F26 DCR1610F24	2800 2600 2400	$ \begin{split} T_{vj} &= -40 \ ^\circ C \ to \ 125 \ ^\circ C, \\ I_{DRM} &= I_{RRM} = 100 \ mA, \\ V_{DRM}, \ V_{RRM} \ t_p &= 10 \ ms, \\ V_{DSM} \ & V_{RSM} = \\ V_{DRM} \ & V_{RSM} + 100 \ V \\ respectively \end{split} $

Lower voltage grades available.

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR1610F28

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

KEY PARAMETERS

V _{DRM}	2800V
I _{T(AV)}	1610 A
ITSM	21500A
dV/dt*	1500V/μs
dl/dt	1000A/µs

* Higher dV/dt selections available

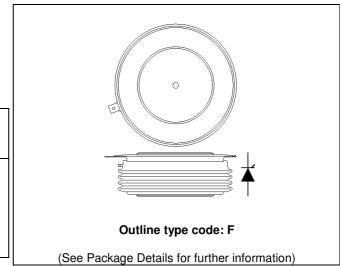


Fig. 1 Package outline

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CURRENT RATINGS

 T_{case} = 60 °C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Si	de Cooled			
I _{T(AV)}	Mean on-state current	Half wave resistive load	1607	А
I _{T(RMS)}	RMS value	-	2524	А
Ι _Τ	Continuous (direct) on-state current	-	2353	А

SURGE RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine, $T_{case} = 125 \degree C$	21.5	kA
l ² t	I ² t for fusing	$V_{R} = 0$	2.3	MA ² s

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Condition	Min.	Max.	Units	
R _{th(j-c)}	Thermal resistance – junction to case	Double side cooled	Double side cooled DC		0.0184	℃/W
		Single side cooled Anode DC Cathode DC		-	0.0333	℃/W
				-	0.0418	°C/W
R _{th(c-h)}	Thermal resistance – case to heatsink	Clamping force 23kN Double side		-	0.004	°C/W
		(with mounting compound) Single side		-	0.008	°C/W
T_{vj}	Virtual junction temperature	On-state (conducting)		-	135	°C
		Reverse (blocking)		-	125	°C
T _{stg}	Storage temperature range			-55	125	°C
Fm	Clamping force			22.0	25.0	kN



DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditio	Min.	Max.	Units	
I _{RRM} /I _{DRM}	Peak reverse and off-state current	At V_{RRM}/V_{DRM} , $T_{case} = 125 ^{\circ}C$	At V _{RRM} /V _{DRM} , T _{case} = 125 °C			mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V _{DRM} , T _j = 125°C, ga	To 67% V_{DRM} , $T_j = 125 °C$, gate open			V/µs
dl/dt	Rate of rise of on-state current	From 67% V_{DRM} to 2x $I_{\text{T}(\text{AV})}$	Repetitive 50Hz	-	250	A/µs
		Gate source $30V$, 10Ω ,	Non-repetitive	-	1000	A/µs
		$t_r < 0.5 \mu s, T_j = 125^\circ\!\!C$				
V _{T(TO)}	Threshold voltage – Low level	100A to 1000A at T _{case} = 128	5°C	-	0.8	V
	Threshold voltage – High level	1000A to 4000A at T _{case} = 12	1000A to 4000A at T _{case} = 125 °C		0.91	V
r _T	On-state slope resistance – Low level	100A to 1000A at T _{case} = 128	-	0.35	mΩ	
	On-state slope resistance – High level	1000A to 4000A at T _{case} = 125 °C		-	0.245	mΩ
t _{gd}	Delay time	$V_D = 67\% V_{DRM}$, gate source 30V, 10 Ω		-	3	μs
		$t_r = 0.5 \mu s, T_j = 25 \ ^\circ C$				
tq	Turn-off time	$T_j = 125 ^{\circ}C, V_R = 100V, dl/dt = 5A/\mu s,$		-	600	μs
		$dV_{DR}/dt = 20V/\mu s$ linear to 25	500V			
Qs	Stored charge	$I_T = 1000A$, tp = 1000us,T _j = 125 °C, dI/dt =5A/µs,		2500	3500	μC
ΙL	Latching current	$T_j = 25 ^{\circ}C, V_D = 5V$		-	3	А
l _Η	Holding current	$T_j = 25 ^{\circ}C, R_{G-K} = \infty, I_{TM} = 50$	0A, I _T = 5A	-	300	mA

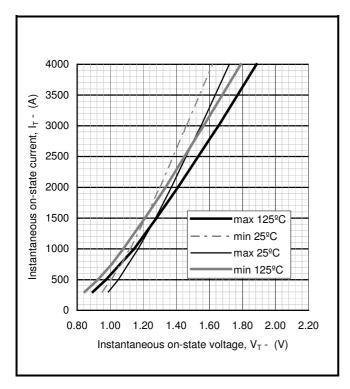


GATE TRIGGER CHARACTERISTICS AND RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
V _{GT}	Gate trigger voltage	$V_{DRM} = 5V, T_{case} = 25 ^{\circ}C$	1.5	V
V_{GD}	Gate non-trigger voltage	At 50% V _{DRM,} T _{case} = 125 ℃	0.4	V
I _{GT}	Gate trigger current	$V_{DRM} = 5V, T_{case} = 25 ^{\circ}C$	250	mA
I _{GD}	Gate non-trigger current	At 50% V _{DRM,} T _{case} = 125℃	10	mA

CURVES

SEMICONDUCTOR





V_{TM} EQUATION

 $V_{TM} = A + Bln (I_T) + C.I_T + D.\sqrt{I_T}$

Where A = 0.746516 B = -0.012797 C = 0.000146 D = 0.010555 these values are valid for $T_j = 125$ °C for I_T 100A to 4000A

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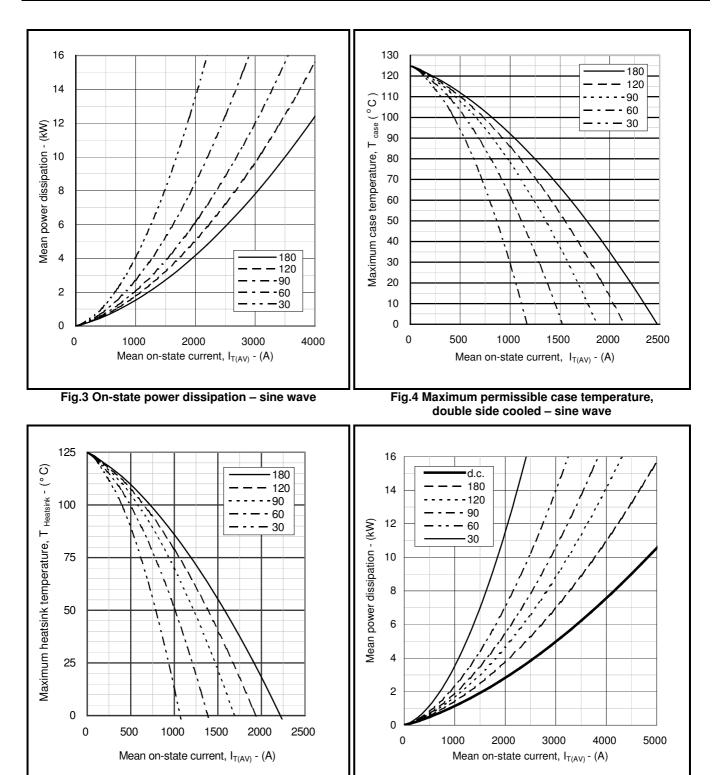
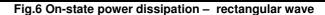


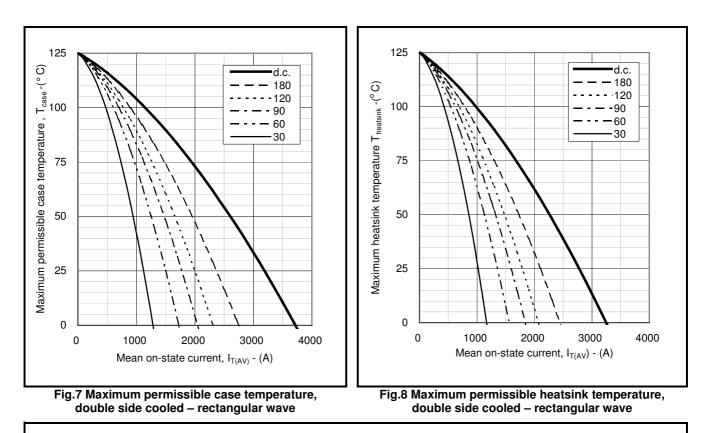
Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

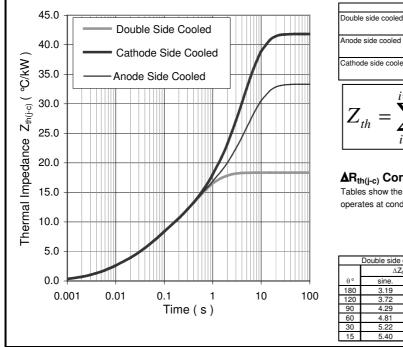


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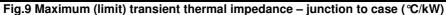
R_i (°C/kW) 7.560 4.0772 3.8420 2.867 $T_i(s)$ 0.687 0.2537 0.0614 0.0101 Anode side coolec R_i (°C/kW) 6.721 4.6219 15.5387 14.8631 T_i (s) 0.1910 0.0158 5.0011 3.3169 Cathode side cooled R_i (°C/kW) 11.5564 8.5810 4.7942 8.3643 T_i (s) 4.2216 6.0269 0.0166 0.2255

$$Z_{th} = \sum_{i=1}^{t=4} [R_i \times (1 - \exp(T/T_i))]$$

$\pmb{\Delta} R_{th(j-c)} \text{ Conduction }$

Tables show the increments of thermal resistance $\mathsf{R}_{\mathsf{th}(j-c)}$ when the device operates at conduction angles other than d.c.

	Double side cooling			Anode Side Cooling			Cathode Sided Cooling			
	ΔZ _{th} ((z)			ΔZ_t	_h (z)		ΔZ_{ti}	n (Z)	
θ°	sine.	rect.		θ°	sine.	rect.	θ°	sine.	rect.	
180	3.19	2.14		180	2.97	2.03	180	2.95	2.02	
120	3.72	3.10		120	3.43	2.89	120	3.40	2.87	
90	4.29	3.64		90	3.92	3.36	90	3.88	3.34	
60	4.81	4.23		60	4.36	3.87	60	4.31	3.84	
30	5.22	4.88		30	4.69	4.41	30	4.64	4.37	
15	5.40	5.22		15	4.84	4.70	15	4.79	4.65	



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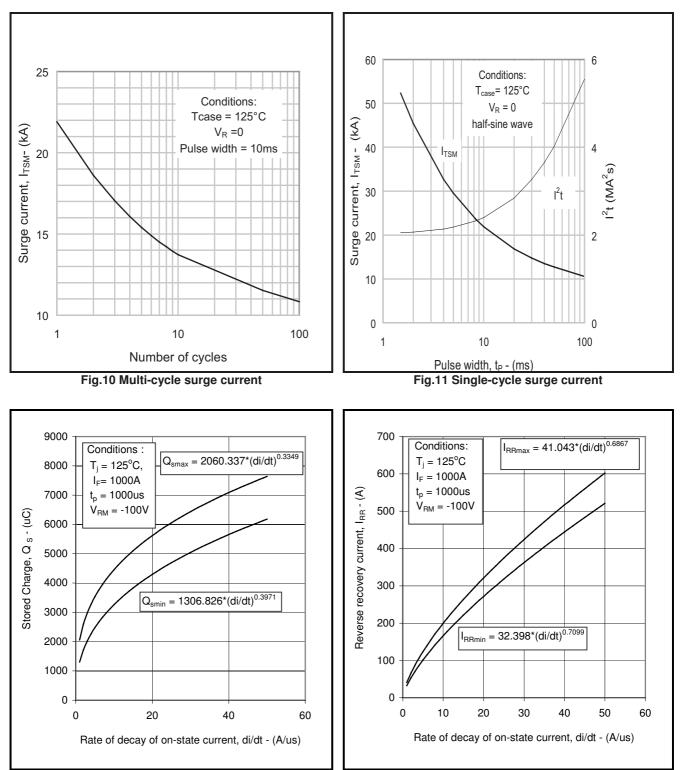


Fig.12 Stored charge vs di/dt

Fig.13 Reverse recovery current vs di/dt

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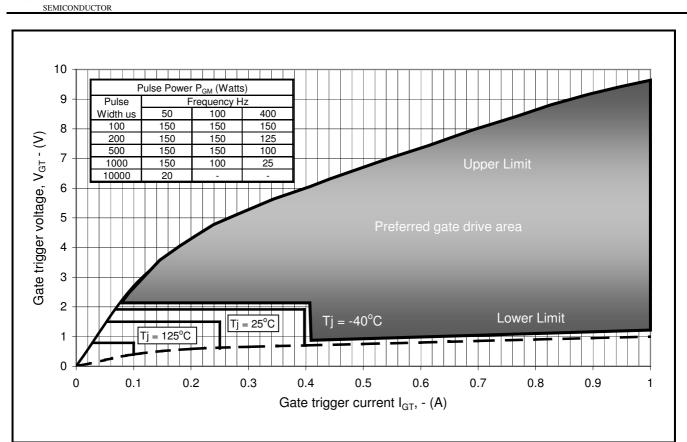


Fig14 Gate Characteristics

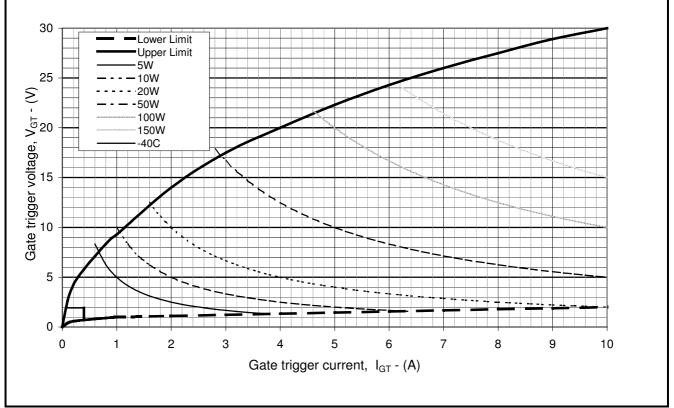


Fig. 15 Gate characteristics

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PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

	Device DCR1003SF18 DCR1006SF28 DCR1008SF36 DCR1020F65 DCR1050SF42 DCR1180F52 DCR1274SF18 DCR1275SF28 DCR1277SF36 DCR1279SF48 DCR1350F42 DCR1640F28 DCR1640F28 DCR1640F28 DCR1830F22 DCR810F85 DCR840F48 DCR890F65 DCR950F65	Maximum Thickness (mm) 26.415 26.49 26.72 27.1 26.72 26.84 26.415 26.49 26.72 26.84 26.72 26.84 26.72 26.49 26.49 26.49 26.415 27.46 26.84 27.1 27.1	Minimum Thickness (mm) 25.865 25.94 26.17 26.55 26.17 26.29 25.865 25.94 26.17 26.29 26.17 26.29 26.17 25.94 25.94 25.94 25.865 26.91 26.29 26.5 26.5				
Lead length: 420mm Lead terminal connector: M4 ring Package outline type code: F							

Fig.16 Package outline



POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



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